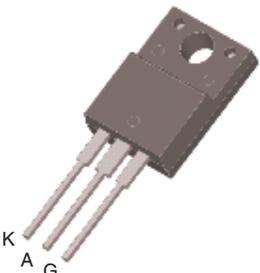
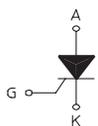


**SENSITIVE GATE SCR**

<p style="text-align: center;"><b>TO220-F (FULLY ISOLATED CASE)</b></p>  <div style="text-align: center; margin-top: 20px;">  </div>	<table style="width: 100%; border-collapse: collapse;"> <tr> <td style="text-align: center;"><b>On-State Current</b></td> <td style="text-align: center;"><b>Gate Trigger Current</b></td> </tr> <tr> <td style="text-align: center;">8 Amp</td> <td style="text-align: center;">&lt; 200 <math>\mu</math>A</td> </tr> <tr> <td colspan="2" style="text-align: center; padding-top: 10px;"><b>Off-State Voltage</b></td> </tr> <tr> <td colspan="2" style="text-align: center;">200 V <math>\div</math> 800 V</td> </tr> </table> <p style="margin-top: 20px;">These series of <b>Silicon Controlled Rectifier</b> use a high performance PNP technology.</p> <p>These parts are intended for general purpose applications where high gate sensitivity is required.</p>	<b>On-State Current</b>	<b>Gate Trigger Current</b>	8 Amp	< 200 $\mu$ A	<b>Off-State Voltage</b>		200 V $\div$ 800 V	
<b>On-State Current</b>	<b>Gate Trigger Current</b>								
8 Amp	< 200 $\mu$ A								
<b>Off-State Voltage</b>									
200 V $\div$ 800 V									

**Absolute Maximum Ratings, according to IEC publication No. 134**

SYMBOL	PARAMETER	CONDITIONS	Value	Unit
$I_{T(RMS)}$	On-state Current	180° Conduction Angle, $T_c = 110\text{ }^\circ\text{C}$	8	A
$I_{T(AV)}$	Average On-state Current	Half Cycle, $\Theta = 180\text{ }^\circ$ , $T_c = 110\text{ }^\circ\text{C}$	5	A
$I_{TSM}$	Non-repetitive On-State Current	Half Cycle, 60 Hz	82	A
$I_{TSM}$	Non-repetitive On-State Current	Half Cycle, 50 Hz	75	A
$I^2t$	Fusing Current	$t_p = 10\text{ms}$ , Half Cycle	28	A <sup>2</sup> s
$I_{GM}$	Peak Gate Current	20 $\mu$ s max.	4	A
$P_{GM}$	Peak Gate Dissipation	20 $\mu$ s max.	5	W
$P_{G(AV)}$	Gate Dissipation	20ms max.	1	W
$T_j$	Operating Temperature		(-40 to +125)	$^\circ\text{C}$
$T_{stg}$	Storage Temperature		(-40 to +150)	$^\circ\text{C}$
$T_{sld}$	Soldering Temperature	10s max.	260	$^\circ\text{C}$
$V_{iso}$	R.M.S. isolation voltage 50/60 Hz sinusoidal waveform		2.500	Vac

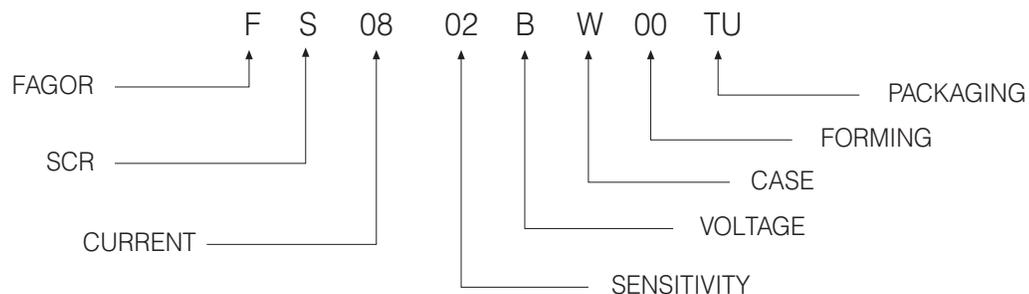
SYMBOL	PARAMETER	CONDITIONS	VOLTAGE					Unit
			B	D	M	S	N	
$V_{DRM}$ $V_{RRM}$	Repetitive Peak Off State Voltage	$R_{GK} = 1\text{ k}\Omega$	200	400	600	700	800	V

## SENSITIVE GATE SCR

### Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	SENSITIVITY		Uni
				02	
$I_{GT}$	Gate Trigger Current	$V_D = 12 V_{DC}, R_L = 140\Omega, T_j = 25^\circ C$	MAX	200	$\mu A$
$V_{GT}$	Gate Trigger Voltage	$V_D = 12 V_{DC}, R_L = 140\Omega, T_j = 25^\circ C$	MAX	0.8	V
$V_{GD}$	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3k\Omega, R_{GK} = 220\Omega, T_j = 125^\circ C$	MIN	0.1	V
$V_{RGM}$	Reverse Gate Voltage	$I_{RG} = 10\mu A,$	MIN	8	V
$I_H$	Holding Current	$I_T = 500 mA,$	MAX	5	mA
$I_L$	Latching Current	$I_G = 1.2 I_{GT}$	MAX	6	mA
$dV / dt$	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, R_{GK} = 1 k\Omega, T_j = 125^\circ C$	MIN	5	V/ $\mu s$
$dI / dt$	Critical Rate of Current Rise	$I_G = 2 \times I_{GT}, tr \leq 100 ns, f = 60 Hz, T_j = 125^\circ C$	MIN	50	A/ $\mu s$
$V_{TM}$	On-state Voltage	at $I_T = 16 Amp, tp = 380 \mu s, T_j = 25^\circ C$	MAX	1.5	V
$V_{t(o)}$	Threshold Voltage	$T_j = 125^\circ C$	MAX	0.85	V
$r_d$	Dynamic resistance	$T_j = 125^\circ C$	MAX	46	$m\Omega$
$I_{DRM} / I_{RRM}$	Off-State Leakage Current	$V_D = V_{DRM}, R_{GK} = 1k\Omega, T_j = 125^\circ C$ $V_R = V_{RRM}, T_j = 25^\circ C$	MAX MAX	0.5 5	mA $\mu A$
$R_{th(j-c)}$	Thermal Resistance Junction-Case for DC	for AC 360° conduction angle		3.5	$^\circ C/W$
$R_{th(j-a)}$	Thermal Resistance Junction-Amb for DC	$S = 1 cm^2$		50	$^\circ C/W$

### PART NUMBER INFORMATION



## SENSITIVE GATE SCR

Fig. 1: Maximum average power dissipation versus average on-state current.

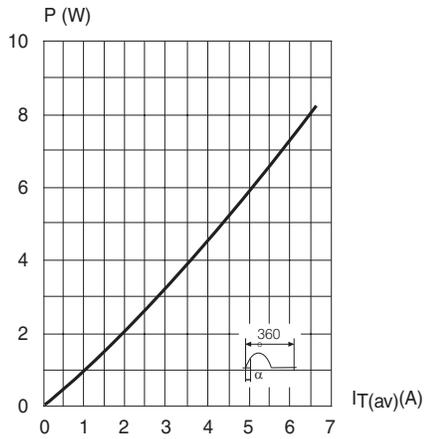


Fig. 3: Relative variation of thermal impedance junction to case versus pulse duration.

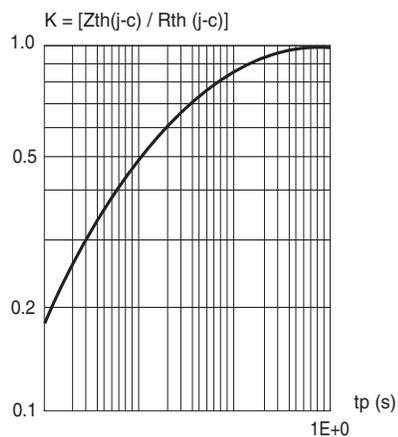


Fig. 5: Relative variation of holding current versus gate-cathode resistance (typical values).

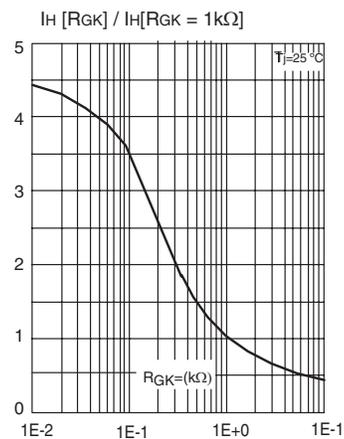


Fig. 2: Average and D.C. on-state current versus case temperature.

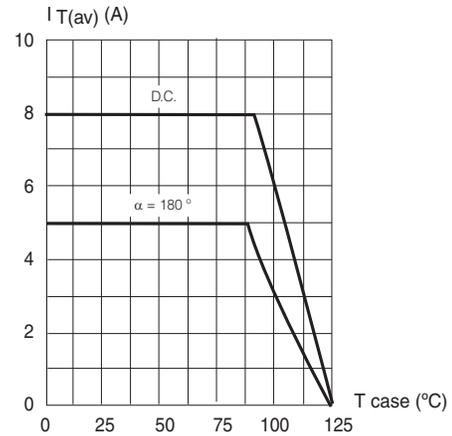


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

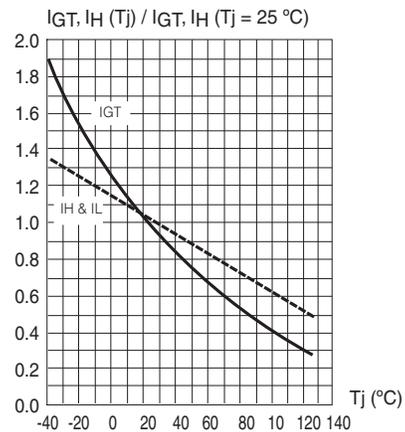
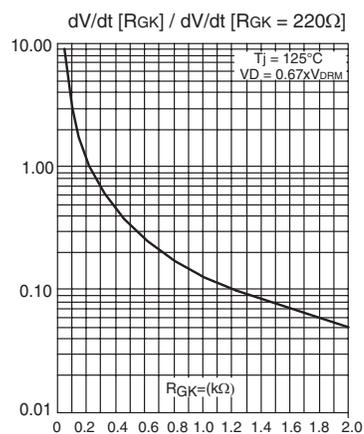


Fig. 6: Relative variation of dV/dt immunity versus gate-cathode resistance (typical values).



**SENSITIVE GATE SCR**

Fig. 7: Relative variation of dV/dt immunity versus gate-cathode resistance (typical values).

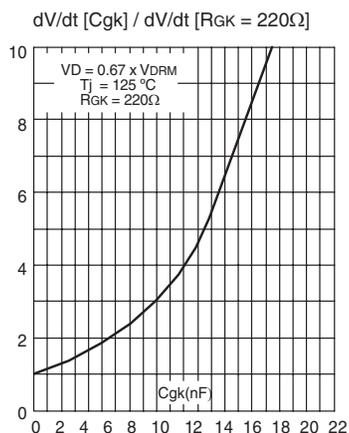


Fig. 8: Non repetitive surge peak on-state current versus number of cycles.

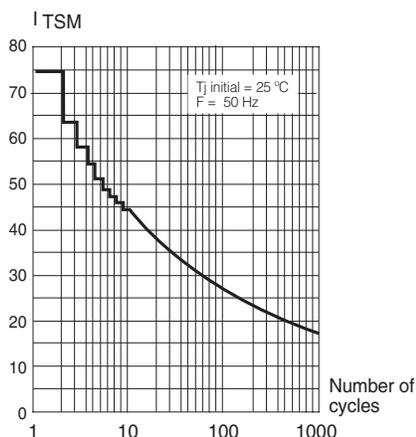


Fig. 9: Non repetitive surge peak on-state current for a sinusoidal pulse with width:  $t_p < 10 \text{ ms}$ , and corresponding value of  $I^2 t$ .

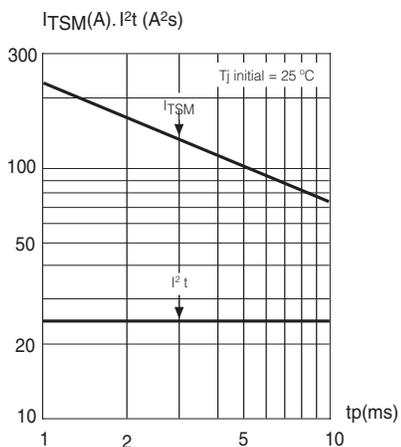
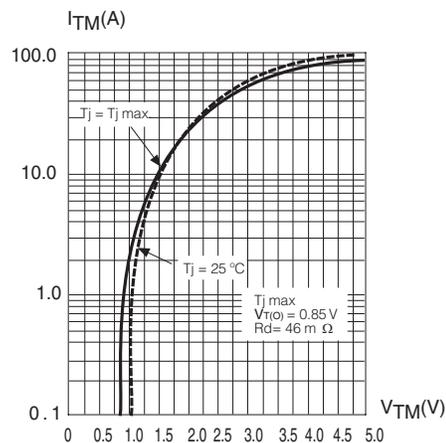


Fig. 10: On-state characteristics (maximum values).



**SENSITIVE GATE SCR**

PACKAGE MECHANICAL DATA TO220-F

